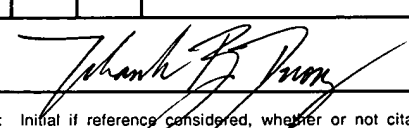


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-1742		SERIAL NO. 09/943,187	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Sally A. Campbell, et al.		GROUP 2810 2822	
					FILING DATE August 29, 2001			
U.S. PATENT & TRADEMARK OFFICE								
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
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FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
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				9/29/02				
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>								

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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Kristy A. Campbell, et al.			
					FILING DATE August 29, 2001		GROUP 2822	
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KBD ↓	AA	09/797,835		Moore			03/01/2001	
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						Yes	No	
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[Signature]				9/29/02				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

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					APPLICANT Kristy A. Campbell, et al.	
					FILING DATE August 29, 2001	GROUP 2818 2822

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*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
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EXAMINER <i>Michael F. Dwyer</i>	DATE CONSIDERED 9/29/02
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09/943,187

APPLICANT
Kristy A. Campbell, et al.

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August 29, 2001

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	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
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KBD	AR	Mitkova, "Insulating and Semiconducting Glasses", Editor: P. Boolchand, World Scientific, New Jersey, 2000, pps. 813-843.
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EXAMINER *John B. Dwyer* DATE CONSIDERED *9/30/02*

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